

Notice of References Cited	Application/Control No. 10/786,093	Applicant(s)/Patent Under Reexamination TOYAMA ET AL.	
	Examiner Seung H. Lee	Art Unit 2876	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,280,161	01-1994	Niwa, Katsuhisa	235/462.42
	C	US-6,601,768	08-2003	McCall et al.	235/462.42
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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